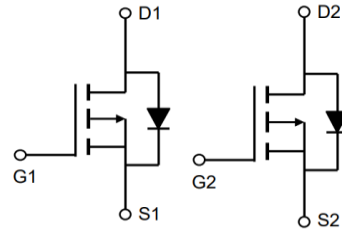


## -30V P+P-Channel Enhancement Mode MOSFET

### Description

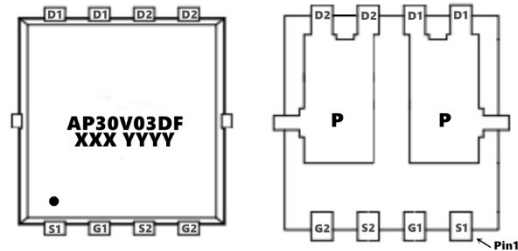
The AP30P03D uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.



### General Features

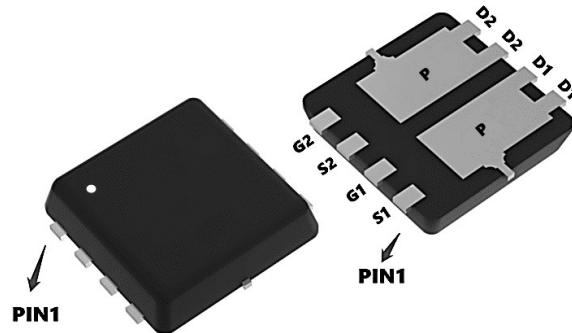
$V_{DS} = -30V$   $I_D = -30A$

$R_{DS(ON)} < 20m\Omega$  @  $V_{GS} = -10V$  (Type: 16m $\Omega$ )



### Application

- Lithium battery protection
- Wireless impact
- Mobile phone fast charging



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP30V03DF	PDFN3*3-8L	AP30V03DF XXX YYYY	5000

### Absolute Maximum Ratings (TC=25°C unless otherwise noted)

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	-30	V
V <sub>GS</sub>	Gate-Source Voltage	±20	V
I <sub>D@TC=25°C</sub>	Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup>	-35	A
I <sub>D@TC=100°C</sub>	Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup>	-22	A
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	-70	A
E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>3</sup>	72.2	mJ
I <sub>AS</sub>	Avalanche Current	-38	A
P <sub>D@TC=25°C</sub>	Total Power Dissipation <sup>4</sup>	34.7	W
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C
R <sub>θJA</sub>	Thermal Resistance Junction-Ambient	62.5	°C/W
R <sub>θJC</sub>	Thermal Resistance Junction-Case <sup>1</sup>	3.6	°C/W



## -30V P-Channel Enhancement Mode MOSFET

### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

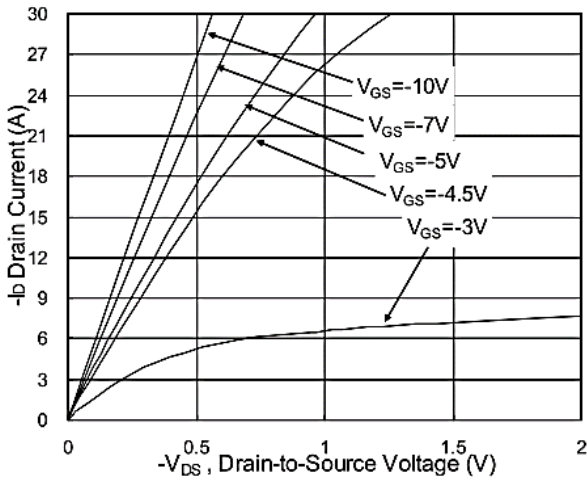
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> = -250μA	-30	-33	-	V
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -30V, V <sub>GS</sub> =0V,	-	-	-1	μA
IGSS	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = -250μA	-1.2	-1.5	-2.5	V
RDS(on)	Static Drain-Source on-Resistance note3	V <sub>GS</sub> = -10V, I <sub>D</sub> = -10A	-	16	20	mΩ
		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -5A	-	25	30	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = -15V, V <sub>GS</sub> =0V, f=1.0MHz	-	1550	-	pF
C <sub>oss</sub>	Output Capacitance		-	327	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	278	-	pF
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = -15V, I <sub>D</sub> = -9.1A, V <sub>GS</sub> = -10V	-	30	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	5.3	-	nC
Q <sub>gd</sub>	Gate-Drain("Miller") Charge		-	7.6	-	nC
td(on)	Turn-on Delay Time	V <sub>DD</sub> = -15V, I <sub>D</sub> = -6A, V <sub>GS</sub> = -10V, R <sub>GEN</sub> =2.5Ω	-	14	-	ns
t <sub>r</sub>	Turn-on Rise Time		-	20	-	ns
td(off)	Turn-off Delay Time		-	95	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	65	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	-10	A
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	-40	A
VSD	Drain to Source Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> = -11A	-	-0.8	-1.2	V

#### Note :

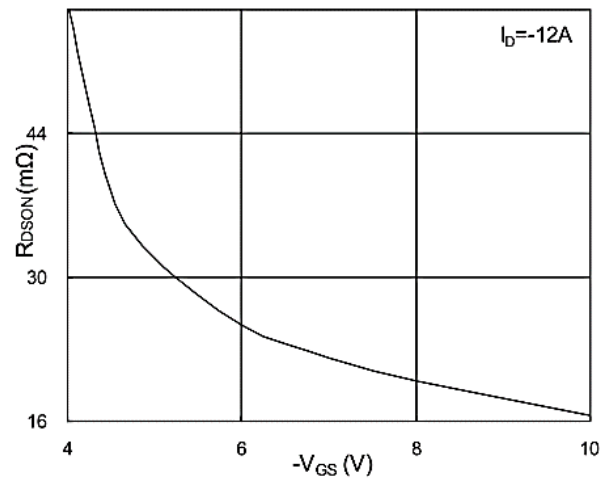
- 1、 The data tested by surface mounted on a 1 inch 2 FR-4 board with 20Z copper.
- 2、 The data tested by pulsed , pulse width ≅ 300us , duty cycle ≅ 2%
- 3、 The EAS data shows Max. rating . The test condition is VDD=-25V,VGS=-10V,L=0.1mH,IAS=-5A
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

**-30V P-Channel Enhancement Mode MOSFET**

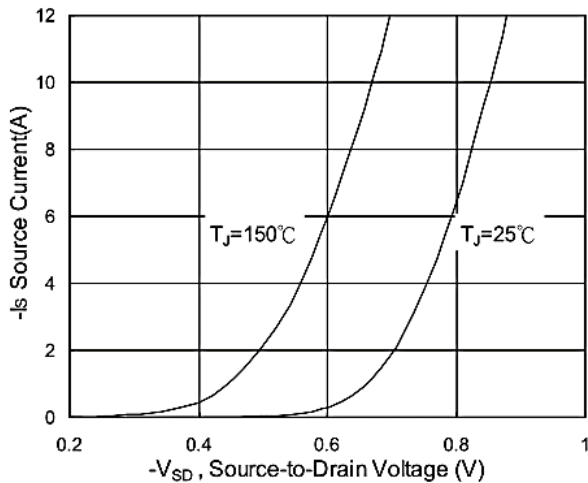
**Typical Characteristics**



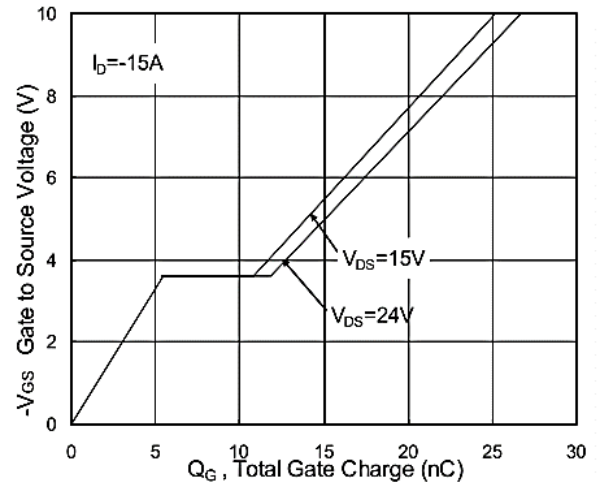
**Fig.1 Typical Output Characteristics**



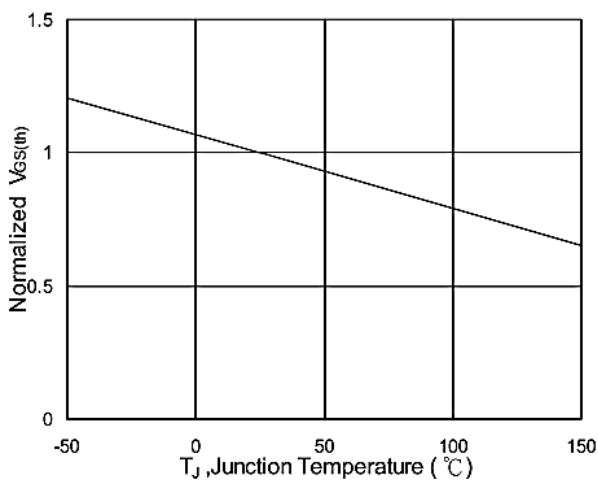
**Fig.2 On-Resistance v.s Gate-Source**



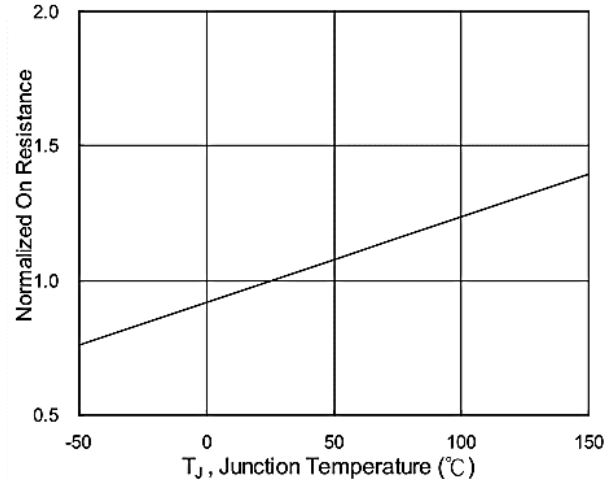
**Fig.3 Forward Characteristics of Reverse**



**Fig.4 Gate-Charge Characteristics**

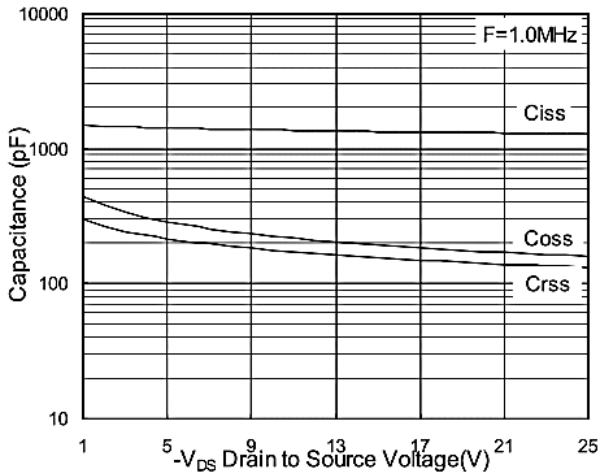


**Fig.5 Normalized  $V_{GS(th)}$  v.s  $T_J$**

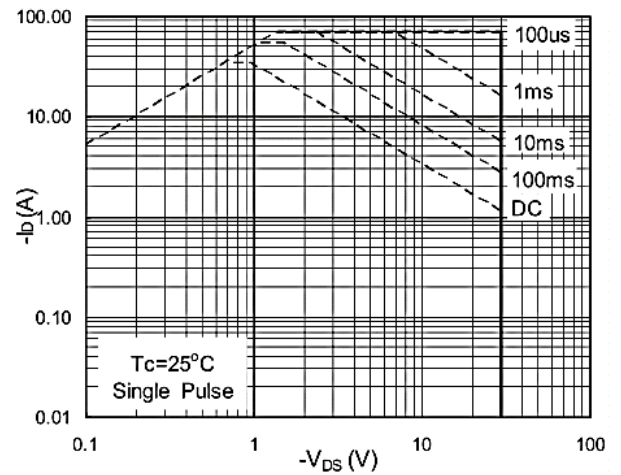


**Fig.6 Normalized  $R_{DS(on)}$  v.s  $T_J$**

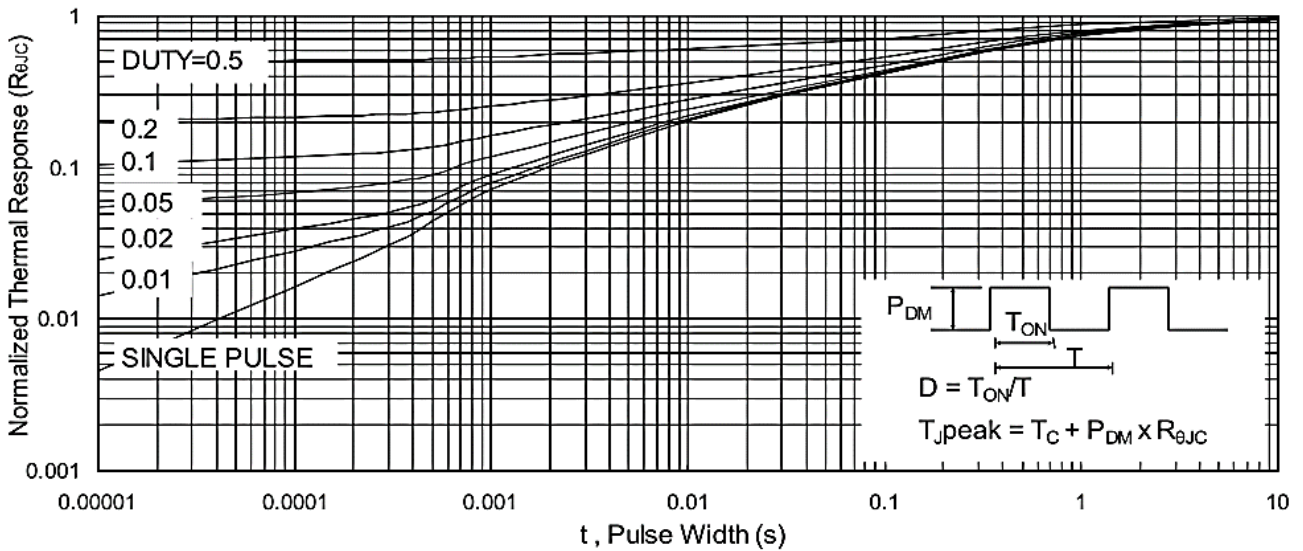
**-30V P-Channel Enhancement Mode MOSFET**



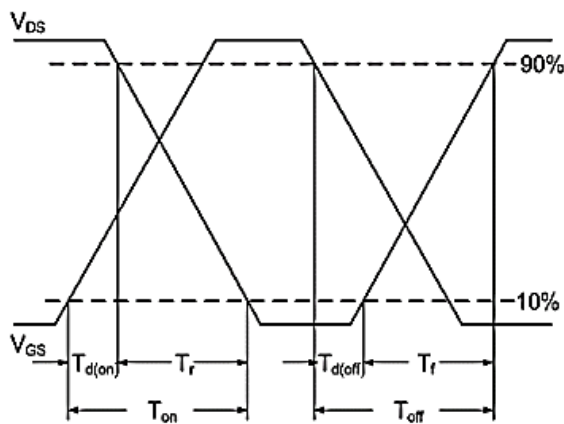
**Fig.7 Capacitance**



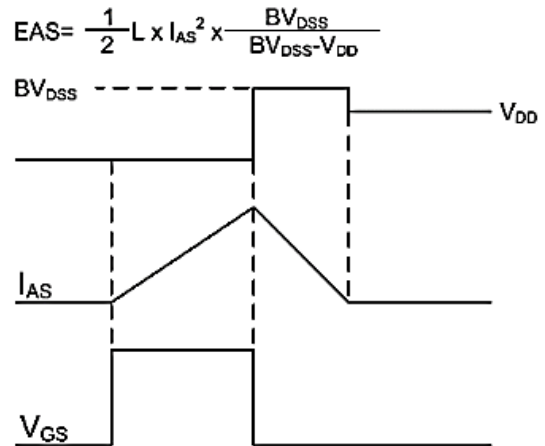
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**



**Fig.10 Switching Time Waveform**

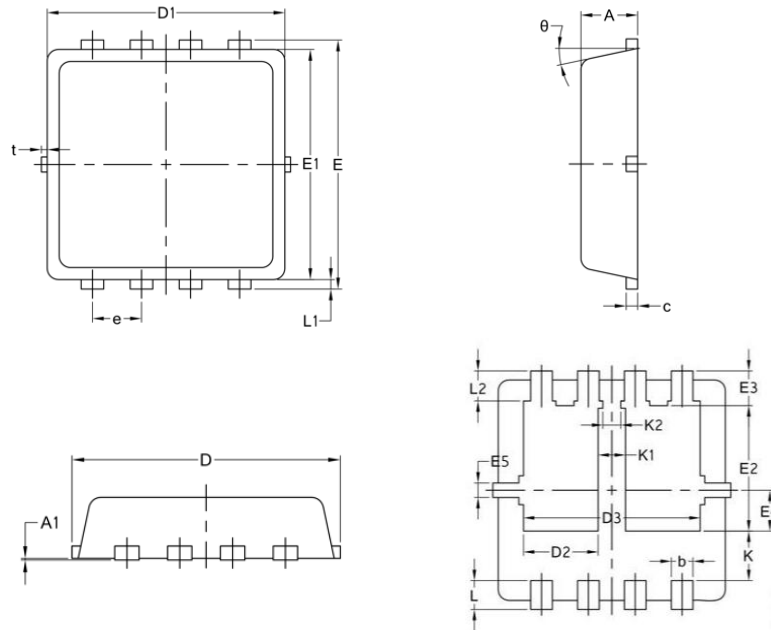


**Fig.11 Unclamped Inductive Switching Waveform**

$$EAS = \frac{1}{2} L \times I_{AS}^2 \times \frac{BV_{DSS}}{BV_{DSS} - V_{DD}}$$

## -30V P-Channel Enhancement Mode MOSFET

### Package Mechanical Data-PDFN3\*3-8L Double



Symbol	Common		
	Mm		
	Min	Nom	Max
A	0.70	0.75	0.85
A1	/	/	0.05
b	0.25	0.30	0.39
c	0.14	0.152	0.20
D	3.20	3.30	3.45
D1	3.05	3.15	3.25
D2	0.84	1.04	1.24
D3	2.30	2.45	2.60
E	3.20	3.30	3.40
E1	2.95	3.05	3.15
E2	1.60	1.74	1.90
E3	0.28	0.48	0.65
E4	0.37	0.57	0.77
E5	0.10	0.20	0.30
e	0.60	0.65	0.70
K	0.50	0.69	0.80
K1	0.30	0.38	0.53
K2	0.15	0.25	0.35
L	0.30	0.40	0.50
L1	0.06	0.125	0.20
L2	0.27	0.42	0.57
t	0	0.075	0.13
Φ	10°	12°	14°